# E·XFL

# Intel - 5SGXEA5N3F40I3LN Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	46080000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea5n3f40i3ln

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

								-,
Transceiver Speed Grade				Core Spe	ed Grade			
	C1	C2, C2L	C3	C4	12, 12L	13, 13L	<b>I</b> 3YY	14
3		Yes	Yes	Yes		Yes	Yes (4)	Yes
GX channel—8.5 Gbps		165	165	165		163	163 17	165

## Table 1. Stratix V GX and GS Commercial and Industrial Speed Grade Offering <sup>(1), (2), (3)</sup> (Part 2 of 2)

Notes to Table 1:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

(3) C2L, I2L, and I3L speed grades are for low-power devices.

(4) I3YY speed grades can achieve up to 10.3125 Gbps.

Table 2 lists the industrial and commercial speed grades for the Stratix V GT devices. **Table 2. Stratix V GT Commercial and Industrial Speed Grade Offering** <sup>(1)</sup>, <sup>(2)</sup>

Transaction Oracle Oracle		Core Speed Grade						
Transceiver Speed Grade	C1	C2	12	13				
2 GX channel—12.5 Gbps GT channel—28.05 Gbps	Yes	Yes	_	_				
3 GX channel—12.5 Gbps GT channel—25.78 Gbps	Yes	Yes	Yes	Yes				

#### Notes to Table 2:

(1) C = Commercial temperature grade; I = Industrial temperature grade.

(2) Lower number refers to faster speed grade.

# **Absolute Maximum Ratings**

Absolute maximum ratings define the maximum operating conditions for Stratix V devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.



Conditions other than those listed in Table 3 may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 3.	Absolute	Maximum	<b>Ratings</b>	for Stratix \	/ Devices	(Part 1 of 2)
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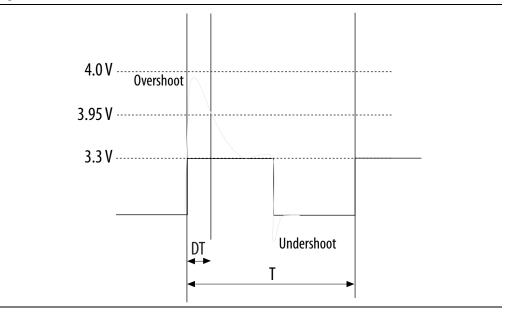
Symbol	Description	Minimum	Maximum	Unit
V <sub>CC</sub>	Power supply for core voltage and periphery circuitry	-0.5	1.35	V
V <sub>CCPT</sub>	Power supply for programmable power technology	-0.5	1.8	V
V <sub>CCPGM</sub>	Power supply for configuration pins	-0.5	3.9	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	-0.5	3.4	V
V <sub>CCBAT</sub>	Battery back-up power supply for design security volatile key register	-0.5	3.9	V
V <sub>CCPD</sub>	I/O pre-driver power supply	-0.5	3.9	V
V <sub>CCIO</sub>	I/O power supply	-0.5	3.9	V

Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

abic J. Maxi				
Symbol	Description	Condition (V)	Overshoot Duration as % @ T <sub>J</sub> = 100°C	Unit
		3.8	100	%
		3.85	64	%
		3.9	36	%
		3.95	21	%
Vi (AC)	AC input voltage	4	12	%
		4.05	7	%
		4.1	4	%
		4.15	2	%
		4.2	1	%

Table 5. Maximum Allowed Overshoot During Transitions

#### Figure 1. Stratix V Device Overshoot Duration



This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)

Symbol	Description	Condition	Min <sup>(4)</sup>	Тур	Max <sup>(4)</sup>	Unit
	Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades)	_	0.87	0.9	0.93	V
V <sub>CC</sub>	Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) <sup>(3)</sup>	_	0.82	0.85	0.88	V
V <sub>CCPT</sub>	Power supply for programmable power technology	_	1.45	1.50	1.55	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	_	2.375	2.5	2.625	V
VI (1)	I/O pre-driver (3.0 V) power supply	_	2.85	3.0	3.15 2.625 3.15 2.625	V
V <sub>CCPD</sub> <sup>(1)</sup>	I/O pre-driver (2.5 V) power supply	-driver (2.5 V) power supply         —         2.375         2.5         2.625         V           fers (3.0 V) power supply         —         2.85         3.0         3.15         V           fers (2.5 V) power supply         —         2.375         2.5         2.625         V	V			
	I/O buffers (3.0 V) power supply		2.85	3.0	3.15	V
V <sub>CCIO</sub>	I/O buffers (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (1.8 V) power supply		1.71	1.8	1.89	V
	I/O buffers (1.5 V) power supply	_	1.425	1.5	1.575	V
	I/O buffers (1.35 V) power supply	_	1.283	1.35	1.45	V
	I/O buffers (1.25 V) power supply	_	1.19	1.25	1.31	V
	I/O buffers (1.2 V) power supply	_	1.14	1.2	1.26	V
	Configuration pins (3.0 V) power supply	_	2.85	3.0	3.15	V
V <sub>CCPGM</sub>	Configuration pins (2.5 V) power supply	_	2.375	2.5	1.55         2.625         3.15         2.625         3.15         2.625         3.15         2.625         1.575         1.45         1.31         1.26	V
	Configuration pins (1.8 V) power supply	_	1.71	1.8	1.89	V
V <sub>CCA_FPLL</sub>	PLL analog voltage regulator power supply	_	2.375	2.5	2.625	V
V <sub>CCD_FPLL</sub>	PLL digital voltage regulator power supply	_	1.45	1.5	1.55	V
V <sub>CCBAT</sub> (2)	Battery back-up power supply (For design security volatile key register)	_	1.2	_	3.0	V
VI	DC input voltage	_	-0.5	_	3.6	V
V <sub>0</sub>	Output voltage	—	0	—	V <sub>CCIO</sub>	V
т	Operating junction temperature	Commercial	0	—		°C
TJ	Operating junction temperature	Industrial	-40	_	100	°C

# I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9. I/	0 Pin Leakage	<b>Current for Stratix </b>	/ Devices <sup>(1)</sup>
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Symbol	Description	Conditions	Min	Тур	Max	Unit
I <sub>I</sub>	Input pin	$V_I = 0 V \text{ to } V_{CCIOMAX}$	-30	—	30	μA
I <sub>0Z</sub>	Tri-stated I/O pin	$V_0 = 0 V \text{ to } V_{\text{CCIOMAX}}$	-30		30	μA

## Note to Table 9:

(1) If  $V_0 = V_{CCIO}$  to  $V_{CCIOMax}$ , 100  $\mu$ A of leakage current per I/O is expected.

## **Bus Hold Specifications**

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

			V <sub>CCI0</sub>										
Parameter	Symbol	Conditions	1.2	2 V	1.	5 V	1.8	B V	2.	5 V	3.0	V	Unit
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I <sub>SUSL</sub>	V <sub>IN</sub> > V <sub>IL</sub> (maximum)	22.5	_	25.0	_	30.0	_	50.0	_	70.0	_	μA
High sustaining current	I <sub>SUSH</sub>	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	-22.5	_	-25.0	_	-30.0	_	-50.0	_	-70.0	_	μA
Low overdrive current	I <sub>odl</sub>	$0V < V_{IN} < V_{CCIO}$	_	120	_	160	_	200	_	300	_	500	μA
High overdrive current	I <sub>odh</sub>	$0V < V_{IN} < V_{CCIO}$		-120		-160	_	-200		-300	_	-500	μA
Bus-hold trip point	V <sub>trip</sub>	_	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

## **On-Chip Termination (OCT) Specifications**

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 1 of 2)

Symbol			Calibration Accuracy				
	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit
25-Ω R <sub>S</sub>	Internal series termination with calibration (25- $\Omega$ setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

			Resistance Tolerance				
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2 V	±35	±35	±50	±50	%
100-Ω R <sub>D</sub>	Internal differential termination (100- $\Omega$ setting)	V <sub>CCPD</sub> = 2.5 V	±25	±25	±25	±25	%

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

# Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} \,=\, R_{SCAL} \Big( 1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big)$$

## Notes to Equation 1:

- (1) The  $R_{OCT}$  value shows the range of OCT resistance with the variation of temperature and  $V_{CCIO}$ .
- (2) R<sub>SCAL</sub> is the OCT resistance value at power-up.
- (3)  $\Delta T$  is the variation of temperature with respect to the temperature at power-up.
- (4)  $\Delta V$  is the variation of voltage with respect to the V<sub>CCIO</sub> at power-up.
- (5) dR/dT is the percentage change of  $R_{\text{SCAL}}$  with temperature.
- (6) dR/dV is the percentage change of  $\mathsf{R}_{\mathsf{SCAL}}$  with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13.	OCT Variation after Power-U	Calibration for Stratix V Devices	(Part 1 of 2) <sup>(1)</sup>
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Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
		3.0	0.0297	
		2.5	0.0344	
dR/dV	OCT variation with voltage without recalibration	1.8	0.0499	%/mV
		1.5	0.0744	
		1.2	0.1241	

# **Switching Characteristics**

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

# **Transceiver Performance Specifications**

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23.	<b>Transceiver S</b>	necifications (	for Stratix	V GX and GS	Devices (1)	(Part 1 of 7)
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Symbol/ Description	Conditions	Trai	isceive Grade	r Speed 1	Trar	isceive Grade	r Speed 2	Trar	isceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
<b>Reference Clock</b>											
Supported I/O Standards	Dedicated reference clock pin	1.2-V	PCML,	1.4-V PCM	L, 1.5-V		, 2.5-V PCN HCSL	1L, Diffe	rential	LVPECL, L\	/DS, and
Standards	RX reference clock pin		1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS								
Input Reference Clock Frequency (CMU PLL) <sup>(8)</sup>	_	40	_	710	40	_	710	40	_	710	MHz
Input Reference Clock Frequency (ATX PLL) <sup>(8)</sup>	_	100		710	100		710	100	_	710	MHz
Rise time	Measure at ±60 mV of differential signal <sup>(26)</sup>	_	_	400	_	_	400	_	_	400	ps
Fall time	Measure at ±60 mV of differential signal <sup>(26)</sup>	of 400			400	_		400	μο		
Duty cycle	—	45		55	45		55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express® (PCIe <sup>®</sup> )	30		33	30		33	30		33	kHz

Symbol/ Description	Conditions	Tra	nsceive Grade	r Speed 1	Tra	nsceive Grade	r Speed 2	Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	85– $\Omega$ setting		85 ± 30%		—	85 ± 30%			85 ± 30%		Ω
Differential on-	100–Ω setting	_	100 ± 30%		_	100 ± 30%		_	100 ± 30%		Ω
chip termination resistors <sup>(21)</sup>	120–Ω setting	_	120 ± 30%		_	120 ± 30%		_	120 ± 30%		Ω
	150-Ω setting	_	150 ± 30%	_	_	150 ± 30%		_	150 ± 30%		Ω
V <sub>ICM</sub> (AC and DC	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V full bandwidth		600		_	600	_		600		mV
	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V half bandwidth	_	600	_	_	600	_	_	600	_	mV
coupled)	V <sub>CCR_GXB</sub> = 1.0 V/1.05 V full bandwidth	_	700		_	700			700		mV
	V <sub>CCR_GXB</sub> = 1.0 V half bandwidth	_	750	_	_	750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(11)</sup>	_	—	—	10	_	—	10	—	—	10	μs
t <sub>LTD</sub> (12)	_	4			4			4			μs
t <sub>LTD_manual</sub> <sup>(13)</sup>		4			4			4	_		μs
t <sub>LTR_LTD_manual</sub> <sup>(14)</sup>		15			15	—		15	—		μs
Run Length	_	_		200		—	200		—	200	UI
Programmable equalization (AC Gain) <sup>(10)</sup>	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)			16	_		16	_		16	dB

 Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 4 of 7)

Symbol/	Conditions	Tra	nsceive Grade	r Speed 1	Transceiver Speed Grade 2			Trar	isceive Grade	r Speed 3	Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	DC Gain Setting = 0		0	_	_	0		_	0	—	dB
	DC Gain Setting = 1	_	2	_	_	2	_	_	2	_	dB
Programmable DC gain	DC Gain Setting = 2	_	4	_	_	4	_	_	4	_	dB
	DC Gain Setting = 3	_	6	_	_	6	_	_	6	_	dB
	DC Gain Setting = 4	_	8	_	_	8	_	_	8	—	dB
Transmitter											
Supported I/O Standards	_				-	I.4-V ar	nd 1.5-V PC	ML			
Data rate (Standard PCS)	_	600	_	12200	600	_	12200	600	_	— 8500/ 10312.5 (24)	
Data rate (10G PCS)	_	600	_	14100	600		12500	600		8500/ 10312.5 (24)	Mbps
	85-Ω setting		85 ± 20%	_	_	85 ± 20%		_	85 ± 20%	_	Ω
Differential on-	100-Ω setting	_	100 ± 20%	_	_	100 ± 20%	_	_	100 ± 20%	_	Ω
chip termination resistors	120-Ω setting	_	120 ± 20%			120 ± 20%		_	120 ± 20%		Ω
	150-Ω setting		150 ± 20%			150 ± 20%			150 ± 20%		Ω
V <sub>OCM</sub> (AC coupled)	0.65-V setting		650		_	650		_	650	_	mV
V <sub>OCM</sub> (DC coupled)	_		650		_	650		_	650	_	mV
Rise time (7)	20% to 80%	30		160	30		160	30		160	ps
Fall time <sup>(7)</sup>	80% to 20%	30		160	30		160	30		160	ps
Intra-differential pair skew	Tx V <sub>CM</sub> = 0.5 V and slew rate of 15 ps			15			15			15 ps	
Intra-transceiver block transmitter channel-to- channel skew	x6 PMA bonded mode			120			120	0 — — 120		ps	

# Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 5 of 7)

Mada (2)	Transceiver	PMA Width	20	20	16	16	10	10	8	8
Mode <sup>(2)</sup>	Speed Grade	PCS/Core Width	40	20	32	16	20	10	16	8
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C3, I3, I3L core speed grade	9.8	9.0	7.84	7.2	5.3	4.7	4.24	3.76
FIFO 3	C1, C2, C2L, I2, I2L core speed grade	8.5	8.5	8.5	8.5	6.5	5.8	5.2	4.72	
	I3YY core speed grade	10.3125	10.3125	7.84	7.2	5.3	4.7	4.24	3.76	
	5	C3, I3, I3L core speed grade	8.5	8.5	7.84	7.2	5.3	4.7	4.24	3.76
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.8	4.2	3.84	3.44
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C3, I3, I3L core speed grade	9.8	9.0	7.92	7.2	4.9	4.5	3.96	3.6
Register		C1, C2, C2L, I2, I2L core speed grade	10.3125	10.3125	10.3125	10.3125	6.1	5.7	4.88	4.56
	3	I3YY core speed grade	10.3125	10.3125	7.92	7.2	4.9	4.5	3.96	3.6
	0	C3, I3, I3L core speed grade	8.5	8.5	7.92	7.2	4.9	4.5	3.96	3.6
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.4	4.1	3.52	3.28

Table 25 shows the approximate maximum data rate using the standard PCS.

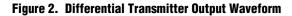
Table 25. Stratix V Standard PCS Approximate Maximum Date Rate (1), (3)

Notes to Table 25:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

(3) The maximum data rate is also constrained by the transceiver speed grade. Refer to Table 1 for the transceiver speed grade.



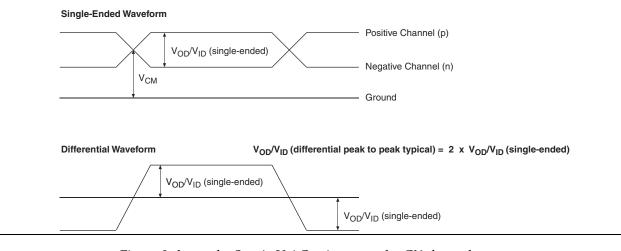


Figure 3 shows the Stratix V AC gain curves for GX channels.

Figure 3. AC Gain Curves for GX Channels (full bandwidth)

Stratix V GT devices contain both GX and GT channels. All transceiver specifications for the GX channels not listed in Table 28 are the same as those listed in Table 23.

Table 28 lists the Stratix V GT transceiver specifications.

# Table 28. Transceiver Specifications for Stratix V GT Devices (Part 2 of 5)<sup>(1)</sup>

Symbol/	Conditions		Transceive Speed Grade			Fransceive Deed Grade		Unit
Description		Min	Тур	Max	Min	Тур	Max	Ī
	100 Hz			-70			-70	
Transmitter REFCLK	1 kHz		_	-90	_	_	-90	-
Phase Noise (622	10 kHz		_	-100	_	_	-100	dBc/Hz
MHz) <sup>(18)</sup>	100 kHz		—	-110	_	—	-110	-
	$\geq$ 1 MHz		—	-120	_	—	-120	-
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(15)</sup>	10 kHz to 1.5 MHz (PCIe)		_	3	_		3	ps (rms)
RREF <sup>(17)</sup>	—		1800 ± 1%	_	_	1800 ± 1%	_	Ω
Transceiver Clocks								
fixedclk <b>clock</b> frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	MHz
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100	_	125	MHz
Receiver				•				
Supported I/O Standards	—		1.4-V PCMI	_, 1.5-V PCM	L, 2.5-V PCI	ML, LVPEC	L, and LVDS	3
Data rate (Standard PCS) <sup>(21)</sup>	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS) <sup>(21)</sup>	GX channels	600	_	12,500	600	_	12,500	Mbps
Data rate	GT channels	19,600	—	28,050	19,600	—	25,780	Mbps
Absolute V <sub>MAX</sub> for a receiver pin <sup>(3)</sup>	GT channels	_	_	1.2	_	_	1.2	V
Absolute V <sub>MIN</sub> for a receiver pin	GT channels	-0.4	_	_	-0.4		_	V
Maximum peak-to-peak	GT channels	_	—	1.6	—	—	1.6	V
differential input voltage V <sub>ID</sub> (diff p-p) before device configuration <sup>(20)</sup>	GX channels				(8)			
	GT channels							
Maximum peak-to-peak differential input voltage $V_{ID}$ (diff p-p) after device configuration ( <sup>16</sup> ), ( <sup>20</sup> )	V <sub>CCR_GTB</sub> = 1.05 V (V <sub>ICM</sub> = 0.65 V)	—	-	2.2	_	_	2.2	V
oomguration ( ), ( )	GX channels		•	•	(8)			
Minimum differential	GT channels	200	_		200			mV
eye opening at receiver serial input pins <sup>(4)</sup> , <sup>(20)</sup>	GX channels				(8)			

Symbol/	Conditions	5	Transceiver Speed Grade			Transceive peed Grade		Unit
Description		Min	Тур	Max	Min	Тур	Max	
Differential on-chip termination resistors <sup>(7)</sup>	GT channels		100	_	_	100	_	Ω
	85- $\Omega$ setting	_	85 ± 30%	_	_	85 ± 30%	_	Ω
Differential on-chip termination resistors	100-Ω setting	_	100 ± 30%	_	_	100 ± 30%	_	Ω
for GX channels <sup>(19)</sup>	120-Ω setting	_	120 ± 30%	_	_	120 ± 30%	_	Ω
	150-Ω setting		150 ± 30%	_	_	150 ± 30%	_	Ω
V <sub>ICM</sub> (AC coupled)	GT channels		650		—	650	—	mV
	VCCR_GXB = 0.85 V or 0.9 V		600	_	_	600		mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 1.0 V full bandwidth	_	700	_	_	700	_	mV
	VCCR_GXB = 1.0 V half bandwidth		750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(9)</sup>	—	—	—	10	—	—	10	μs
t <sub>LTD</sub> <sup>(10)</sup>		4			4			μs
t <sub>LTD_manual</sub> <sup>(11)</sup>	—	4	—	—	4	—	_	μs
t <sub>LTR_LTD_manual</sub> <sup>(12)</sup>	_	15			15	—		μs
Run Length	GT channels	_	_	72	—	—	72	CID
nun Lengin	GX channels				(8)			
CDR PPM	GT channels			1000	_	—	1000	± PPM
	GX channels				(8)			
Programmable	GT channels	_	_	14	—	—	14	dB
equalization (AC Gain) <sup>(5)</sup>	GX channels				(8)			
Programmable	GT channels	_	—	7.5	—	—	7.5	dB
DC gain <sup>(6)</sup>	GX channels				(8)			
Differential on-chip termination resistors <sup>(7)</sup>	GT channels	_	100	_	_	100	_	Ω
Transmitter	·1							
Supported I/O Standards	_			1.4-V	and 1.5-V F	PCML		
Data rate (Standard PCS)	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS)	GX channels	600		12,500	600	_	12,500	Mbps

# Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5)<sup>(1)</sup>

Symbol	Parameter	Min	Тур	Max	Unit
+ (3) (4)	Input clock cycle-to-cycle jitter ( $f_{REF} \ge 100 \text{ MHz}$ )	_	—	0.15	UI (p-p)
t <sub>INCCJ</sub> <sup>(3),</sup> <sup>(4)</sup>	Input clock cycle-to-cycle jitter (f <sub>REF</sub> < 100 MHz)	-750	_	+750	ps (p-p)
t	Period Jitter for dedicated clock output (f_{OUT} $\geq$ 100 MHz)	_	_	175 <sup>(1)</sup>	ps (p-p)
t <sub>outpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output (f <sub>OUT</sub> < 100 MHz)	_		17.5 <sup>(1)</sup>	mUI (p-p)
+ (5)	Period Jitter for dedicated clock output in fractional PLL ( $f_{0UT} \geq 100 \mbox{ MHz})$	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
t <sub>foutpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
+	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{OUT} \ge 100 \text{ MHz}$ )	_	_	175	ps (p-p)
t <sub>outccj_dc</sub> <sup>(5)</sup>	Cycle-to-Cycle Jitter for a dedicated clock output (f <sub>0UT</sub> < 100 MHz)	_	_	17.5	mUI (p-p)
<b>+</b> <i>(5)</i>	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL (f_{OUT} $\geq$ 100 MHz)	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
t <sub>FOUTCCJ_DC</sub> <sup>(5)</sup>	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )+	_	_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
t <sub>OUTPJ_IO</sub> (5), ii (8) F	Period Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} $\geq$ 100 MHz)	_	_	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O (f <sub>OUT</sub> < 100 MHz)	_	_	60	mUI (p-p)
t <sub>FOUTPJ_IO</sub> (5),	Period Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} \ge 100 \text{ MHz}$ )	_	_	600 (10)	ps (p-p)
(8), (11)	Period Jitter for a clock output on a regular I/O in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>outccj_io</sub> (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} $\geq$ 100 MHz)	_	_	600	ps (p-p)
(8)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ( $f_{OUT}$ < 100 MHz)	_	_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>foutccj_10</sub> <sup>(5),</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{0UT} \geq 100 \mbox{ MHz})$	_	_	600 <sup>(10)</sup>	ps (p-p)
(8), (11)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )	_	_	60	mUI (p-p)
t <sub>casc_outpj_dc</sub>	Period Jitter for a dedicated clock output in cascaded PLLs (f_{0UT} $\geq$ 100 MHz)		_	175	ps (p-p)
(5), (6)	Period Jitter for a dedicated clock output in cascaded PLLs (f <sub>OUT</sub> < 100 MHz)		_	17.5	mUI (p-p)
f <sub>DRIFT</sub>	Frequency drift after PFDENA is disabled for a duration of 100 $\mu s$	_	±10	%	
dK <sub>BIT</sub>	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k <sub>value</sub>	Numerator of Fraction	128	8388608	2147483648	

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

0h.a.l	Conditions		C1		C2,	C2L, I	2, I2L	C3, I3, I3L, I3YY			C4,14			11
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Transmitter	•													•
	SERDES factor J = 3 to 10 (9), (11), (12), (13), (14), (15), (16)	(6)	_	1600	(6)	_	1434	(6)	_	1250	(6)	_	1050	Mbps
	$\begin{array}{c} \text{SERDES factor J} \\ \geq 4 \end{array}$													
True Differential I/O Standards - f <sub>HSDR</sub> (data rate)	LVDS TX with DPA <sup>(12)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	(6)		1600	(6)		1600	(6)	_	1600	(6)	_	1250	Mbps
	SERDES factor J = 2,	(6)		(7)	(6)		(7)	(6)		(7)	(6)		(7)	Mbps
	uses DDR Registers	(0)	_	(7)	(0)		(7)	(0)	_	(7)	(0)	_	(7)	wups
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)		(7)	(6)		(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f <sub>HSDR</sub> (data rate) <sup>(10)</sup>	SERDES factor J = 4 to 10 $(17)$	(6)		1100	(6)		1100	(6)		840	(6)		840	Mbps
t <sub>x Jitter</sub> - True Differential	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_	_	160	_	_	160			160	_		160	ps
I/O Standards	Total Jitter for Data Rate < 600 Mbps	_	_	0.1	_	_	0.1	_	_	0.1	_	_	0.1	UI
t <sub>x Jitter</sub> - Emulated Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_	_	300	_	_	300	_	_	300	_	_	325	ps
with Three External Output Resistor Network	Total Jitter for Data Rate < 600 Mbps	_		0.2			0.2			0.2	_		0.25	UI

# Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 2 of 4)

Family	Device	Package	Package Configuration .rbf Size (bits)				
Stratix V E <sup>(1)</sup>	5SEE9	—	342,742,976	700,888			
	5SEEB	_	342,742,976	700,888			

## Table 47. Uncompressed .rbf Sizes for Stratix V Devices

## Notes to Table 47:

(1) Stratix V E devices do not have PCI Express® (PCIe®) hard IP. Stratix V E devices do not support the CvP configuration scheme.

(2) 36-transceiver devices.

(3) 24-transceiver devices.

(4) File size for the periphery image.

(5) The IOCSR .rbf size is specifically for the CvP feature.

Use the data in Table 47 to estimate the file size before design compilation. Different configuration file formats, such as a hexadecimal (.hex) or tabular text file (.ttf) format, have different file sizes. For the different types of configuration file and file sizes, refer to the Quartus II software. However, for a specific version of the Quartus II software, any design targeted for the same device has the same uncompressed configuration file size. If you are using compression, the file size can vary after each compilation because the compression ratio depends on your design.

• For more information about setting device configuration options, refer to *Configuration, Design Security, and Remote System Upgrades in Stratix V Devices.* For creating configuration files, refer to the *Quartus II Help.* 

Table 48 lists the minimum configuration time estimates for Stratix V devices.

Variant	Member		Active Serial <sup>(1)</sup>		Fast Passive Parallel <sup>(2)</sup>				
	Member Code	Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)		
	A3	4	100	0.534	32	100	0.067		
	AS	4	100	0.344	32	100	0.043		
	A4	4	100	0.534	32	100	0.067		
	A5	4	100	0.675	32	100	0.084		
	A7	4	100	0.675	32	100	0.084		
GX	A9	4	100	0.857	32	100	0.107		
	AB	4	100	0.857	32	100	0.107		
	B5	4	100	0.676	32	100	0.085		
	B6	4	100	0.676	32	100	0.085		
	B9	4	100	0.857	32	100	0.107		
	BB	4	100	0.857	32	100	0.107		
ст	C5	4	100	0.675	32	100	0.084		
GT	C7	4	100	0.675	32	100	0.084		

Table 54 lists the PS configuration timing parameters for Stratix V devices.

Table 54. PS Timing Parameters for Stratix V Devices

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μS
t <sub>status</sub>	nSTATUS low pulse width	268	1,506 <sup>(1)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> (5)	nCONFIG high to first rising edge on DCLK	1,506	—	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t <sub>DH</sub>	DATA[] hold time after rising edge on DCLK	0	—	ns
t <sub>CH</sub>	DCLK high time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CL</sub>	DCLK low time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>	—	S
f <sub>MAX</sub>	DCLK frequency	—	125	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode $(3)$	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

## Notes to Table 54:

(1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

(3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section.

(5) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

# Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

Table 55. Initialization Clock Source Option and the Maximu	m Frequency
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Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles <sup>(1)</sup>		
Internal Oscillator	AS, PS, FPP	12.5 MHz			
CLKUSR	AS, PS, FPP <sup>(2)</sup>	125 MHz	8576		
DCLK	PS, FPP	125 MHz			

# Notes to Table 55:

(1) The minimum number of clock cycles required for device initialization.

(2) To enable CLKUSR as the initialization clock source, turn on the Enable user-supplied start-up clock (CLKUSR) option in the Quartus II software from the General panel of the Device and Pin Options dialog box.

# **Remote System Upgrades**

Table 56 lists the timing parameter specifications for the remote system upgrade circuitry.

Table 56. Remote System Upgrade Circuitry Timing Specifications	Table 56.	<b>Remote System</b>	Upgrade Circuitry	y Timing S	<b>Specifications</b>
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Parameter	Minimum	Maximum	Unit
t <sub>RU_nCONFIG</sub> <sup>(1)</sup>	250	—	ns
t <sub>RU_nRSTIMER</sub> <sup>(2)</sup>	250	—	ns

#### Notes to Table 56:

- (1) This is equivalent to strobing the reconfiguration input of the ALTREMOTE\_UPDATE megafunction high for the minimum timing specification. For more information, refer to the Remote System Upgrade State Machine section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (2) This is equivalent to strobing the reset\_timer input of the ALTREMOTE\_UPDATE megafunction high for the minimum timing specification. For more information, refer to the User Watchdog Timer section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

# **User Watchdog Internal Circuitry Timing Specification**

Table 57 lists the operating range of the 12.5-MHz internal oscillator.

## Table 57. 12.5-MHz Internal Oscillator Specifications

Minimum	Typical	Maximum	Units
5.3	7.9	12.5	MHz

# I/O Timing

Altera offers two ways to determine I/O timing—the Excel-based I/O Timing and the Quartus II Timing Analyzer.

Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis. The Quartus II Timing Analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after you complete place-and-route.

 You can download the Excel-based I/O Timing spreadsheet from the Stratix V Devices Documentation web page.

# **Programmable IOE Delay**

Table 58 lists the Stratix V IOE programmable delay settings.

Table 58. IOE Programmable Delay for Stratix V Devices (Part 1 of 2)

Deremeter	Available	Min Fast Model Slow Model										
Parameter (1)	Available Settings	Offset (2)	Industrial	Commercial	C1	C2	C3	C4	12	13, 13YY	14	Unit
D1	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D2	32	0	0.230	0.244	0.415	0.415	0.459	0.503	0.417	0.456	0.500	ns

Parameter	Available	Min	Fast	Fast Model Slow Model								
(1)	Settings	<b>Offset</b> (2)	Industrial	Commercial	C1	C2	C3	C4	12	13, 13YY	14	Unit
D3	8	0	1.587	1.699	2.793	2.793	2.992	3.192	2.811	3.047	3.257	ns
D4	64	0	0.464	0.492	0.838	0.838	0.924	1.011	0.843	0.920	1.006	ns
D5	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D6	32	0	0.229	0.244	0.415	0.415	0.458	0.503	0.418	0.456	0.499	ns

#### Notes to Table 58:

(1) You can set this value in the Quartus II software by selecting D1, D2, D3, D5, and D6 in the Assignment Name column of Assignment Editor.

(2) Minimum offset does not include the intrinsic delay.

# **Programmable Output Buffer Delay**

Table 59 lists the delay chain settings that control the rising and falling edge delays of the output buffer. The default delay is 0 ps.

Table 55. Flugiallillable Uulput Duffel Delay für Stratix V Devices'	Table 59.	). Programmable Output Buffer Delay for	r Stratix V Devices (†
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Symbol	Parameter	Typical	Unit
D <sub>OUTBUF</sub>	Rising and/or falling edge delay	0 (default)	ps
		25	ps
		50	ps
		75	ps

Note to Table 59:

(1) You can set the programmable output buffer delay in the Quartus II software by setting the Output Buffer Delay Control assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the Output Buffer Delay assignment.

# Glossary

Table 60 lists the glossary for this chapter.

Table 60. Glossary (Part 1 of 4)

Letter	Subject	Definitions	
Α			
В	—	—	
С			
D	_	_	
E	—	—	
F	f <sub>HSCLK</sub>	Left and right PLL input clock frequency.	
	f <sub>HSDR</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDR</sub> = 1/TUI), non-DPA.	
	f <sub>hsdrdpa</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDRDPA</sub> = 1/TUI), DPA.	

Letter	Subject	Definitions	
V	V <sub>CM(DC)</sub>	DC common mode input voltage.	
	V <sub>ICM</sub>	Input common mode voltage—The common mode of the differential signal at the receiver.	
	V <sub>ID</sub>	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.	
	V <sub>DIF(AC)</sub>	AC differential input voltage—Minimum AC input differential voltage required for switching.	
	V <sub>DIF(DC)</sub>	DC differential input voltage— Minimum DC input differential voltage required for switching.	
	V <sub>IH</sub>	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.	
	V <sub>IH(AC)</sub>	High-level AC input voltage	
	V <sub>IH(DC)</sub>	High-level DC input voltage	
	V <sub>IL</sub>	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.	
	V <sub>IL(AC)</sub>	Low-level AC input voltage	
	V <sub>IL(DC)</sub>	Low-level DC input voltage	
	V <sub>OCM</sub>	Output common mode voltage—The common mode of the differential signal at the transmitter.	
	V <sub>OD</sub>	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.	
	V <sub>SWING</sub>	Differential input voltage	
	V <sub>X</sub>	Input differential cross point voltage	
	V <sub>OX</sub>	Output differential cross point voltage	
W	W	High-speed I/O block—clock boost factor	
X			
Y	_	_	
Z			

# Table 60. Glossary (Part 4 of 4)